# 1<sup>st</sup> Workshop on Applied Software Reliability

## In Conjunction with the International Conference on Dependable Systems and Networks www.dsn.org

## **Monday June 26, 2006**

Sheraton Society Hill, Philadelphia, PA, USA

Research on software reliability has been active for several decades now and has produced massive amount of literature to explore new ideas, and system prototypes to experiment with the proposed ideas. Notwithstanding this proficiency, only in a few instances has research work found its way into industrial applications. This apparent uncoordination is exacerbated by the increasing need for quality and dependability guarantees in the more and more computerized modern world.

The Workshop on Applied Software Reliability (WASR) is the first workshop dedicated to addressing the increasing gap between practitioners and researchers involved in the development of mission critical, software-intensive systems. The workshop will provide a forum for detailed exchange of ideas, techniques, and experiences with the goal of understanding the industry's trend towards fielding reliable applications and providing feedback on existing and potential approaches.

This workshop will focus on exploring answers to key research questions, including:

- What are the reliability requirements of current and future applications?
- What are the important challenges and risks?
- What are the currently used approaches to address reliability issues in industrial applications and what is needed?
- What are the promising reliability solutions in a short-mid term time frame?
- What are the open research problems?

Researchers and practitioners from academia, industry, and the government are welcome and encouraged to participate. We are soliciting contributions in application areas including, but not limited to:

- Database applications
- Scientific applications
- Telecommunication applications
- Internet applications
- Embedded applications
- Space applications

## **Workshop format**

This one-day workshop will be divided into 3 subsequent sessions organized by topic. There will be both invited papers and solicited papers. Each session will consist of 3 paper presentations (20 minutes each) plus one panel discussion (30 minutes). Panelists will include paper presenters and invited speakers.

### **Submission information**

Submitted papers must be original work with no substantially overlap with papers that have been published or that are simultaneously submitted to a journal or conference with proceedings. Papers should be at most 6 pages in IEEE proceedings style (two-column pages, single space, using 10-point font and 1-inch margins) including all figures and references. Each submission should start with a title, a short abstract, and names and contact information of the authors. Submissions must be made electronically in PDF or Postscript format by sending an email to adnan@isi.edu with cbasile@lucent.com in cc.

Submitted papers will be fully refereed by PC members. Accepted papers will be published in the supplement volume of DSN 2006 proceedings. Authors of accepted papers must guarantee that their paper will be presented at the workshop.

### **Important Dates**

Paper submission due March 7, 2006 (Tuesday)
Acceptance notification April 4, 2006 (Tuesday)
Camera-ready version of papers due April 18, 2006 (Tuesday)

## **Program Committee**

### **Program Co-Chairs:**

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